

Application No.: 09/867,766

**AMENDMENT TO CLAIMS**

Please amend the claims as follows:

1. (Currently amended) A semiconductor integrated circuit comprising:
  - a ROM for storing plural confidential data thereon address by address ~~which cannot be read from outside of the integrated circuit~~ which can be read only from an internal circuit inside of the integrated circuit;
  - a tester for testing the ROM address by address; and
  - a storage device for storing plural redundancy check data address by address that have been obtained by performing a predetermined calculation on each of the corresponding plural confidential data,wherein the tester includes a checker for performing the same calculation as the predetermined calculation on each of the plural confidential data that has been read out from the ROM address by address,
- wherein a result of the calculation performed by the checker is compared to each of the corresponding plural redundancy check data stored in the storage device address by address,
- wherein the storage device is included in the ROM, and
- wherein the plural redundancy check data and each of the corresponding plural confidential data are stored at mutually different addresses on the ROM.

2-4. (Cancelled)

5. (Currently amended) A method of testing a semiconductor integrated circuit including a ROM that stores plural confidential data thereon address by address and ~~cannot be read out~~

**Application No.: 09/867,766**

~~from the integrated circuit~~ which can be read only from an internal circuit inside of the integrated circuit, the method comprising the steps of:

a) storing plural redundancy check data, which have been obtained by performing a predetermined calculation on each of the corresponding plural confidential data, in a redundancy check data storage device of the integrated circuit;

b) reading out each of the plural confidential data from the ROM address by address and performing the same calculation as the predetermined calculation on each of the plural confidential data read out; and

c) reading out each of the corresponding plural redundancy check data from the storage device address by address and comparing a result of the calculation performed in the step b) to each of the corresponding plural redundancy check data read out,

wherein the storage device is included in the ROM, and

wherein the plural redundancy check data and each of the corresponding plural confidential data are stored at mutually different addresses on the ROM.